

Abstract of the Disclosure:

A method and device for measuring voltage of an internal reference voltage source of an integrated semiconductor circuit, in particular, a DRAM, including the steps of

- 5 comparing a reference voltage to an external comparison voltage with a comparator, forming a measured value for the reference voltage to be set in accordance with a comparison result, switching a commutator by a clock- or software-control to alternatively apply the reference voltage and the
- 10 comparison voltage to the comparator inputs at the same time, varying one of the reference and comparison voltage to a setpoint voltage value until the comparator output changes its logic value at each commutator switched stage, buffering the voltage values present for each switched state when the logic
- 15 value changes, forming an average value for the reference voltage from the stored voltage values, and setting the reference voltage as a function of the average value formed.

GLM/vs